

PART NUMBER 93425ADMB-ROCS

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All re-creations are done with the approval of the Original Component Manufacturer. (OCM)

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - Class V Space Level

Qualified Suppliers List of Distributors (QSLD)

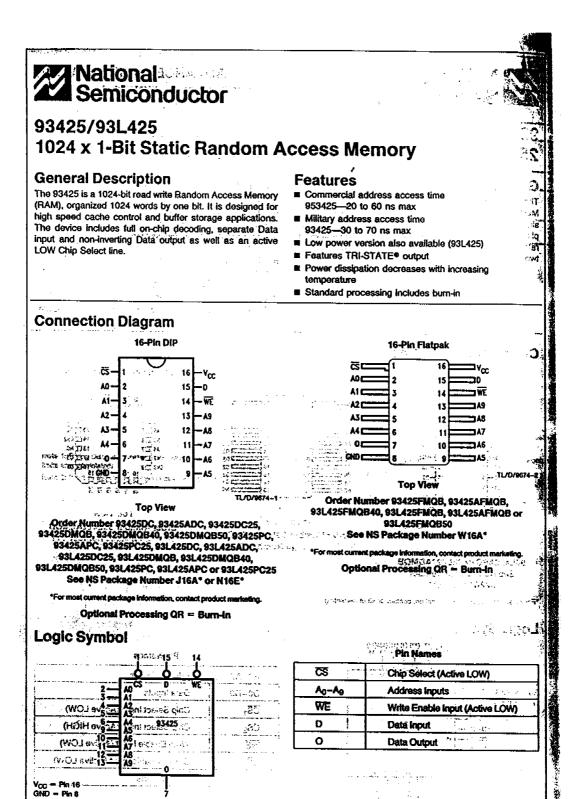
 Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OCM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.

National Semiconductor is now part of Texas Instruments.

Search http://www.ti.com/ for the latest technical information and details on our current products and services.



6-38

TL/D/9674-3

TABLE 5

Absolute Maximum Ratings

Above which the useful life may be impaired

Storage Temperature

-65°C to +150°C

Supply Voltage Range Input Voltage (DC) (Note 1) -0.5V to +7.0V-0.5V to V_{CC}

Voltage Applied to Outputs

(Note 2)

-0.5V to +5.5V

Lead Temperature (Soldering, 10 sec.) Maximum Junction Temperature (TJ)

300°C +175°C + 20 mA

Output Current Input Current (DC)

-12 mA to +5,0 mA

Guaranteed Operating Ranges

Supply Voltage (V_{CC})

Commercial Military

5.0V ±5% 5.0V ± 10%

Case Temperature (T_C)

Commercial Military

0°C to +75°C -55°C to +125°C

DC Electrical Characteristics Over operating temperature ranges (Note 3)

Output LOW Voltage Input HIGH Voltage			0.45	14			
Input HIGH Voltage			0.40	V	V _{CC} = Min, I _{OL} = 16 mA		
·	2.1			٧	Guaranteed Input HIGH Voltage for All Inputs (Notes 4, 5 & 6)		
Input LOW Voltage			8.0	٧	Guaranteed Input LOW Voltage for All Inputs (Notes 4, 5 & 6)		
Output HIGH Voltage	2.4			٧	V _{CC} = Max, I _{OH} = -5.2 mA		
Input LOW Current		- 180	-300	μΑ	V _{CC} = Max, V _{IN} = 0.4V		
Input HIGH Current		1.0	40	μΑ	V _{CC} = Max, V _{IN} = 4.5V		
Input Breakdown Current			1.0	mA	V _{CC} = Max, V _{IN} = V _{CC}		
Input Diode Clamp Voltage		-1.0	1.5	٧	V _{CC} = Max, V _{IN} = -10 mA		
Output Current (HIGH Z)			50 50	μА	V _{CC} = Max, V _{OUT} = 2.4V V _{CC} = Max, V _{OUT} = 0.5V		
Output Current Short Circuit to Ground (Note 7)			-100	∍mA	V _{CC} = Max, (Note 7)		
Power Supply Current		60	65		93L425 Commercial		
		00	75	mA	93L425 Military		
ļ				mA	99425 Commercial 93425 Military		
	Output HIGH Voltage Input LOW Current Input HIGH Current Input Breakdown Current Input Diode Clamp Voltage Output Current (HIGH Z) Output Current Short Circuit to Ground (Note 7)	Output HIGH Voltage 2.4 Input LOW Current Input HIGH Current Input Breakdown Current Input Diode Clamp Voltage Output Current (HIGH Z) Output Current Short Circuit to Ground (Note 7)	Output HIGH Voltage Input LOW Current -180 Input HIGH Current 1.0 Input Breakdown Current Input Diode Clamp Voltage -1.0 Output Current (HIGH Z) Output Current Short Circuit to Ground (Note 7)	Output HIGH Voltage Input LOW Current Input HIGH Current Input Breakdown Current Input Diode Clamp Voltage Output Current (HIGH Z) Output Current Short Circuit to Ground (Note 7) Power Supply Current 0.8 -180 -300 1.0 40 -1.0 -1.5 50 -50 -50 -100 66	0.8 V		

Note 1: Either input voltage limit or input current limit is sufficient to protect the inputs.

Hote 2: Output current limit required.

Note 3: Typical values are at $V_{\rm CC}$ = 5.0V. $T_{\rm C}$ = +25°C and maximum loading.

Note 4: Static condition only.

Note & Functional testing done at input levels $V_{IL} = V_{OL\ Max}$ (0.45V), $V_{IH} = V_{OH\ Min}$ (2.4V).

Note 6: AC testing done at input levels $V_{RI} = 3V$, $V_{R_c} = 0V$.

Note 7: Short circuit to ground not to exceed one second.

Note 8: The maximum address access time is guaranteed to be the worst case bit in the memory using a pseudorandom testing pattern.

Note 9: t_W measured at $t_{WSA} = Min. t_{WSA}$ measured at $t_W = Min.$

93425/93L425

	nercial ectrical Characteristics (No	te 6) V _{CC} = 5.0V ±	5%, GI	4D = 0V,	, T _C = 0	C to +	75°C		AC AC
Symbol	Parameter	Conditions	1.	25-35	93L42 93L4	25A	93	.425-60 3L425	/ Units
EAD TIM!	NO.		Min	Mak	Min	Max	Min	Ma	186 F
		(Figures 3a, 3b)	\dashv	25		30	-4-	1 46	729
ACS	Chip Select Access Time Chip Select to HIGH Z	(rigules sa, su)	+	25	-	30	1	Ac	
tzrcs	· · · · · · · · · · · · · · · · · · ·		\rightarrow	35		45	-+	60	1,00
t _{AA}	Address Access Time (Note 8)		+	499	• • •	7.5		\ '/	<u> </u>
VRITE TIM	Write Pulse Width to Guarantee Writing	(Figures 4a, 4b)	30	/	35		45	\forall	ns
	(Note 9)			\				- - - - - - - - - - 	
twsp	Data Setup Time prior to Write		5 /	 	5		5	/ _	ns/
t _{WHD}	Data Hold Time after Write		5/		5		5	44-	ns/
^t WSA	. Address Setup Time prior to Write (Note 9)		5		5		19	$\perp \! \! \perp$	ns as
twha	Address Hold Time after Write		 		5			$\perp \perp$	ATIS/
twscs	Chip Select Setup Time prior to Write		5		5		5	\	30s/
twics.	Chip Select Hold Time after Write		5		5	<u></u>	5		\ ::::::::::::::::::::::::::::::::::::
		1 .	π	7		'	17	1	5\ ns
tzws	Write Enable to HIGH Z		1/	20		25	И	4	ol ms
WR Milita	Write Recovery Time	oto 6) Vee = 5 0V	10%	30	V To a	35	∀	4	1
Milita AC E	Write Recovery Time	ote 6) V _{CC} = 5.0V :	1	30	93L4	35	93	4	5 \ n3
Milita AC E	Write Recovery Time Iry Iectrical Characteristics (N		1	30 \	93L4	35 55°C	93	125°C L425-7 3L425	5 \ ns
Milita AC E	Write Recovery Time Iry Iectrical Characteristics (N Parameter	Conditions	93L	30 \ GND = 0	93L4 93L	35 55°C 125-50 A25A	93	125°C L425-7 3L425	5 \ ns
MILITA AC E Symbol READ TIM	Write Recovery Time Iry Iectrical Characteristics (N Parameter	Conditions	93L	30 \ GND = 0	93L4 93L	35 55°C 125-50 A25A	93	125°C 125°C 1425-7 31425	5 \ ns
MILITER AC E Symbol READ TIM	Write Recovery Time Iry Iectrical Characteristics (N Parameter ING	Conditions	93L Min	30 GND - (425-40 Max	93L4 93L	35 = -55°C 125-50 A25A Max	93 Min	125°C L425-7)3L425	5 N
MILITA AC E Symbol READ TIM tacs tzrcs	Write Recovery Time IPY Iectrical Characteristics (N Parameter ING Chip Select Access Time	Conditions (Figures 3a, 3b)	93L Min	30 GND = (93L/ 93L Min	35 55°C 125-50 A25A Max	93 Min	125°C L425-7 3L425	5 B)
MILITER AC E Symbol READ TIM	Write Recovery Time ITY Iectrical Characteristics (N Parameter ING Chip Select Access Time Chip Select to HIGH Z Address Access Time (Note 8)	Conditions (Figures 3a, 3b)	93L Min	30 GND = (425-40 Max 30 25 40	93L/ 93L Min	35 55°C 125-50 425A Max 35 30 60	93 Mir	125°C L425-7 3L425	5 BS
Milita AC E Symbol READ TIM tacs tzrcs	Write Recovery Time LTY Iectrical Characteristics (N Parameter ING Chip Select Access Time Chip Select to HIGH Z Address Access Time (Note 8)	Conditions (Figures 3a, 3b)	93L Min	30 GND = (425-40 Max 30 25 40	93LA 93L Min	35 55°C 125-50 A25A Max 35 30 60	93 94 Mir	125°C L425-7 3L425-7 3L425-7	5 BS
MILITAR AC E Symbol READ TIM LACS LACS LACS LACS WRITE TIM LACS LACS LACS LACS LACS LACS LACS LACS	Write Recovery Time ITY Iectrical Characteristics (N Parameter ING Chip Select Access Time Chip Select to HIGH Z Address Access Time (Note 8) WiNG Write Pulse Width to Guarantee Writing (Note 9)	Conditions (Figures 3a, 3b)	93L Min	30 GND = (425-40 Max 30 25 40	93L 93L Min	35 55°C 125-50 A25A Max 35 30 60	93 9 Mir	125°C L425-7 31_425 1 M.	5 B
Milita AC E Symbol READ TIM LACS LZRCS LAA WRITE TIM LWSD	Write Recovery Time ITY Iectrical Characteristics (N Parameter ING Chip Select Access Time Chip Select to HIGH Z Address Access Time (Note 8) Write Pulse Width to Guarantee Writing	Conditions (Figures 3a, 3b)	93L Min	30 GND = (425-40 Max 30 25 40	93L4 93L Min	35 55°C 125-50 A25A Max 35 30 60	93 94 Mir	125°C L425-7 SL425-7 M	TO / Unit ak wide Size Tr. Size Tr.
MILITAR AC E Symbol READ TIM LACS LACS LACS LACS WRITE TIM LACS LACS LACS LACS LACS LACS LACS LACS	IPY Iectrical Characteristics (N Parameter ING Chip Select Access Time Chip Select to HIGH Z Address Access Time (Note 8) With Pulse Width to Guarantee Writing (Note 9) Data Setup Time prior to Write Data Hold Time after Write Address Setup Time prior to Write	Conditions (Figures 3a, 3b)	93L Min 35	30 GND = (425-40 Max 30 25 40	93L/ 93L Min 40	35 55°C 125-50 A25A Max 35 30 /- 60	93 Min 50	125°C L425-7 3L425 1 M.	TO / Unit ak wide Size Tr. Size Tr.
MILITAR AC E Symbol READ TIM LACS LACS LAC WRITE TIL LW LWSD LWHD LWSA	IPY lectrical Characteristics (N Parameter ING Chip Select Access Time Chip Select to HIGH Z Address Access Time (Note 8) WING Write Pulse Width to Guarantee Writing (Note 9) Data Setup Time prior to Write Data Hold Time after Write Address Setup Time prior to Write (Note 9)	Conditions (Figures 3a, 3b)	93L Min 35 5 5	30 GND = (425-40 Max 30 25 40	93L/ 93L Min 40 5	35 55°C 125-50 A25A Max 35 30 /- 60	93 9 Miles	125°C L425-7 3L425-7 1 Ma	TO / Unit ak wide Size Tr. Size Tr.
MILITAR AC E Symbol READ TIM LACS LZRCS LAC WRITE TIL LW LWSD LWHD LWSA	IPY Iectrical Characteristics (N Parameter ING Chip Select Access Time Chip Select to HIGH Z Address Access Time (Note 8) Write Pulse Width to Guarantee Writing (Note 9) Data Setup Time prior to Write Data Hold Time after Write Address Setup Time prior to Write (Note 9)	Conditions (Figures 3a, 3b)	93L Min 35 5 5	30 GND = (425-40 Max 30 25 40	93L 93L Min 40 5 5	35 55°C 125-50 A25A Max 35 30 /- 60	93 9 Military 10 10 10 10 10 10 10 10 10 10 10 10 10	125°C L425-7 3L425-7 1 M.	5 BS
MILITAR AC E Symbol READ TIM LACS LACS LAC WRITE TIL LW LWSD LWHD LWSA LWHA LWSCS	IPY Iectrical Characteristics (N Parameter ING Chip Select Access Time Chip Select to HIGH Z Address Access Time (Note 8) MING Write Pulse Width to Guarantee Writing (Note 9) Data Setup Time prior to Write Data Hold Time after Write Address Setup Time prior to Write (Note 9) Address Hold Time after Write Chip Select Setup Time prior to Write	Conditions (Figures 3a, 3b)	93L Min 35 5 5 5	30 GND = (425-40 Max 30 25 40	93L 93L Min 40 5 5 10 5	35 55°C 125-50 A25A Max 35 30 /- 60	93 93 94 94 95 96 96 97 97 97 97 97 97 97 97 97 97 97 97 97	125°C L425-7 3L425-7 1 M	5 BS
MILITAL AC E Symbol READ TIM LACS LACS LAC WRITE TII LW LWSD LWHD LWSA LWHA LWSCS LWHCS	IPY Iectrical Characteristics (N Parameter ING Chip Select Access Time Chip Select Access Time (Note 8) Write Pulse Width to Guarantee Writing (Note 9) Data Setup Time prior to Write Data Hold Time after Write Address Setup Time prior to Write (Note 9) Address Hold Time after Write Chip Select Setup Time prior to Write Chip Select Hold Time after Write	Conditions (Figures 3a, 3b)	93L Min 35 5 5	30 \ GND = (425-40 \ Max \ 30 \ 25 \ 40 \ \ Max \ 30 \ 25 \ 30 \ 30 \ 30 \ 30 \ 30 \ 30 \ 30 \ 3	93L 93L Min 40 5 5	35 55°C 125-50 A25A Max 35 30 	93 94 94 94 95 96 96 97 97 97 97 97 97 97 97 97 97 97 97 97	125°C L425-7 3L425-7 3L425-7 1 Ma	5 BS
MILITAR AC E Symbol READ TIM LACS LACS LAC WRITE TIL LW LWSD LWHD LWSA LWHA LWSCS	IPY Iectrical Characteristics (N Parameter ING Chip Select Access Time Chip Select to HIGH Z Address Access Time (Note 8) MING Write Pulse Width to Guarantee Writing (Note 9) Data Setup Time prior to Write Data Hold Time after Write Address Setup Time prior to Write (Note 9) Address Hold Time after Write Chip Select Setup Time prior to Write	Conditions (Figures 3a, 3b)	93L Min 35 5 5 5	30 GND = (425-40 Max 30 25 40	93L 93L Min 40 5 5 10 5	35 55°C 125-50 A25A Max 35 30 /- 60	93 94 94 94 95 96 96 97 97 97 97 97 97 97 97 97 97 97 97 97	125°C L425-7 3L425-7 3L425-7 1 Ma	5 BS

6-42

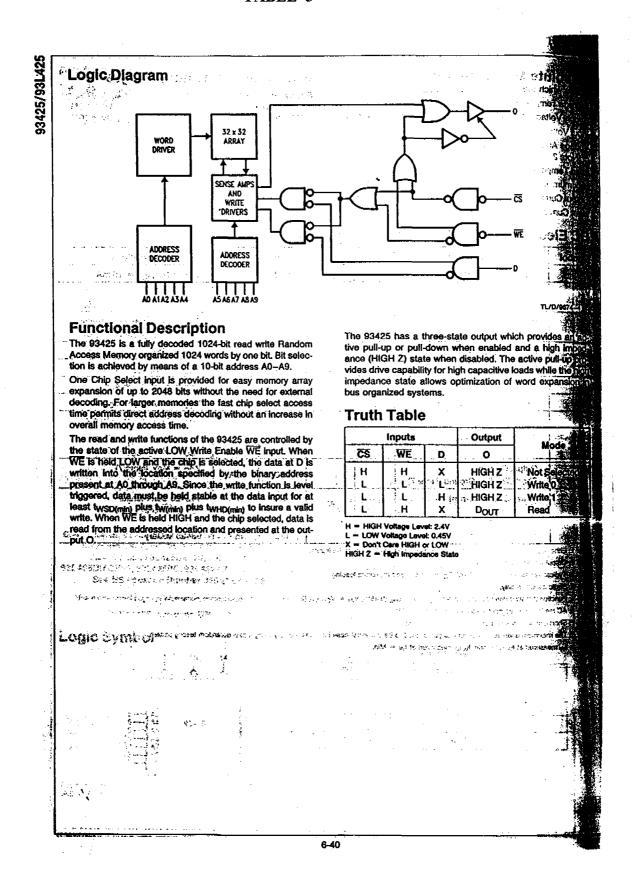


TABLE 5

